

**Features**

- Low power, pin-compatible replacement for LCX and LPT families
- 5V tolerant inputs and outputs
- 24 mA balanced drive outputs
- Power-off disable outputs permits live insertion
- Edge-rate control circuitry for reduced noise
- FCT-C speed at 4.1 ns
- Latch-up performance exceeds JEDEC standard no. 17
- Typical output skew < 250ps
- Industrial temperature range of -40°C to +85°C
- TSSOP (19.6-mil pitch) or SSOP (25-mil pitch)
- Typical  $V_{Olp}$  (ground bounce) performance exceeds Mil Std 883D
- $V_{CC} = 2.7V$  to  $3.6V$
- ESD (HBM) > 2000V

**CY74FCT163H245**

- Bus hold on data inputs
- Eliminates the need for external pull-up or pull-down resistors
- Devices with bus hold are not recommended for translating rail-to-rail CMOS signals to 3.3V logic levels

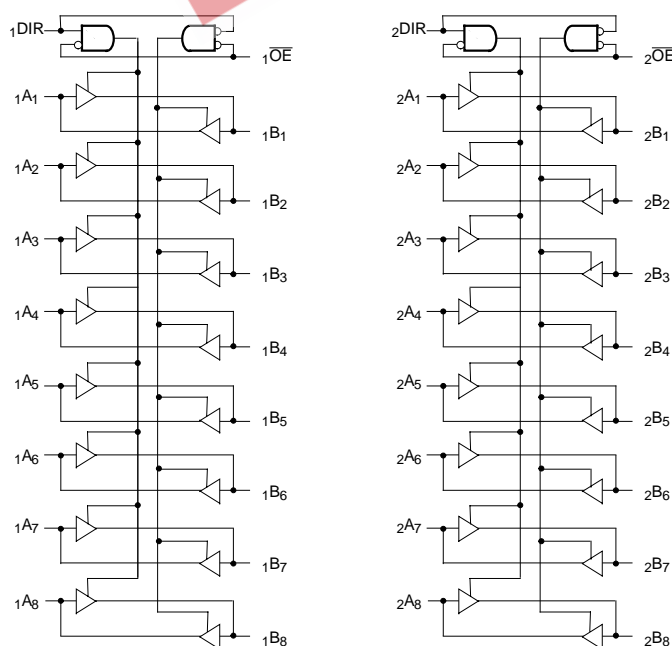
**Functional Description**

These 16-bit transceivers are designed for use in bidirectional synchronous communication between two buses, where high speed and low power are required. Direction of data flow is controlled by (DIR), the Output Enable ( $\overline{OE}$ ) transfers data when LOW and isolates the buses when HIGH. The outputs are 24-mA balanced output drivers with current limiting resistors to reduce the need for external terminating resistors and provide for minimal undershoot and reduced ground bounce..

The CY74FCT163H245 has "bus hold" on the data inputs, which retains the input's last state whenever the input goes to high impedance. This eliminates the need for pull-up/down resistors and prevents floating inputs.

The CY74FCT163245 is designed with inputs and outputs capable of being driven by 5.0V buses, allowing its use in mixed voltage systems as a translator. The outputs are also designed with a power off disable feature enabling its use in applications requiring live insertion.

**Logic Block Diagrams CY74FCT163245, CY74FCT163H245**



**Pin Configuration**

**SSOP/TSSOP  
Top View**

1DIR	1	48	1OE
1B1	2	47	1A1
1B2	3	46	1A2
GND	4	45	GND
1B3	5	44	1A3
1B4	6	43	1A4
VCC	7	42	VCC
1B5	8	41	1A5
1B6	9	40	1A6
GND	10	39	GND
1B7	11	38	1A7
1B8	12	37	1A8
2B1	13	36	2A1
2B2	14	35	2A2
GND	15	34	GND
2B3	16	33	2A3
2B4	17	32	2A4
VCC	18	31	VCC
2B5	19	30	2A5
2B6	20	29	2A6
GND	21	28	GND
2B7	22	27	2A7
2B8	23	26	2A8
2DIR	24	25	2OE

**Pin Description**

Name	Description
$\overline{OE}$	Three-State Output Enable Inputs (Active LOW)
DIR	Direction Control
A	Inputs or Three-State Outputs <sup>[1]</sup>
B	Inputs or Three-State Outputs <sup>[1]</sup>

**Function Table<sup>[2]</sup>**

Inputs		Outputs
$\overline{OE}$	DIR	
L	L	Bus B Data to Bus A
L	H	Bus A Data to Bus B
H	X	High Z State

**Maximum Ratings<sup>[3, 4]</sup>**

(Above which the useful life may be impaired. For user guidelines, not tested.)

Storage Temperature .....	-55°C to +125°C
Ambient Temperature with Power Applied.....	-55°C to +125°C
Supply Voltage Range .....	0.5V to 4.6V
DC Input Voltage .....	-0.5V to +7.0V
DC Output Voltage.....	-0.5V to +7.0V
DC Output Current (Maximum Sink Current/Pin) .....	-60 to +120 mA
Power Dissipation .....	1.0W

**Operating Range**

Range	Ambient Temperature	V <sub>CC</sub>
Industrial	-40°C to +85°C	2.7V to 3.6V

**Electrical Characteristics for Non Bus Hold Devices** Over the Operating Range V<sub>CC</sub>=2.7V to 3.6V

Parameter	Description	Test Conditions	Min.	Typ. <sup>[5]</sup>	Max.	Unit
V <sub>IH</sub>	Input HIGH Voltage	All Inputs	2.0		5.5	V
V <sub>IL</sub>	Input LOW Voltage				0.8	V
V <sub>H</sub>	Input Hysteresis <sup>[6]</sup>			100		mV
V <sub>IK</sub>	Input Clamp Diode Voltage	V <sub>CC</sub> =Min., I <sub>IN</sub> =-18 mA		-0.7	-1.2	V
I <sub>IH</sub>	Input HIGH Current	V <sub>CC</sub> =Max., V <sub>I</sub> =5.5			±1	µA
I <sub>IL</sub>	Input LOW Current	V <sub>CC</sub> =Max., V <sub>I</sub> =GND			±1	µA
I <sub>OZH</sub>	High Impedance Output Current (Three-State Output pins)	V <sub>CC</sub> =Max., V <sub>OUT</sub> =5.5V			±1	µA
I <sub>OZL</sub>	High Impedance Output Current (Three-State Output pins)	V <sub>CC</sub> =Max., V <sub>OUT</sub> =GND			±1	µA
I <sub>OS</sub>	Short Circuit Current <sup>[7]</sup>	V <sub>CC</sub> =Max., V <sub>OUT</sub> =GND	-60	-135	-240	mA
I <sub>OFF</sub>	Power-Off Disable	V <sub>CC</sub> =0V, V <sub>OUT</sub> ≤4.5V			±100	µA
I <sub>CC</sub>	Quiescent Power Supply Current	V <sub>IN</sub> ≤0.2V, V <sub>IN</sub> ≥V <sub>CC</sub> -0.2V			0.1	µA
ΔI <sub>CC</sub>	Quiescent Power Supply Current (TTL inputs HIGH)	V <sub>IN</sub> =V <sub>CC</sub> -0.6V <sup>[8]</sup>			2.0	µA

**Note:**

- On the CY74FCT163H245, these pins have bus hold.
- H = HIGH Voltage Level. L = LOW Voltage Level. X = Don't Care. Z = High Impedance.
- Operation beyond the limits set forth may impair the useful life of the device. Unless otherwise noted, these limits are over the operating free-air temperature range.
- Unused inputs must always be connected to an appropriate logic voltage level, preferably either V<sub>CC</sub> or ground.
- Typical values are at V<sub>CC</sub>=3.3V, T<sub>A</sub> = +25°C ambient.
- This parameter is specified but not tested.
- Not more than one output should be shorted at a time. Duration of short should not exceed one second. The use of high-speed test apparatus and/or sample and hold techniques are preferable in order to minimize internal chip heating and more accurately reflect operational values. Otherwise prolonged shorting of a high output may raise the chip temperature well above normal and thereby cause invalid readings in other parametric tests. In any sequence of parameter tests, I<sub>OS</sub> tests should be performed last.
- Per TTL driven input; all other inputs at V<sub>CC</sub> or GND.

**Electrical Characteristics For Bus Hold Devices** Over the Operating Range  $V_{CC}=2.7V$  to  $3.6V$ 

Parameter	Description	Test Conditions	Min.	Typ. <sup>[5]</sup>	Max.	Unit
$V_{IH}$	Input HIGH Voltage	All Inputs	2.0		$V_{CC}$	V
$V_{IL}$	Input LOW Voltage				0.8	V
$V_H$	Input Hysteresis <sup>[6]</sup>			100		mV
$V_{IK}$	Input Clamp Diode Voltage	$V_{CC}=\text{Min.}, I_{IN}=-18\text{ mA}$		-0.7	-1.2	V
$I_{IH}$	Input HIGH Current	$V_{CC}=\text{Max.}, V_I=V_{CC}$			$\pm 100$	$\mu\text{A}$
$I_{IL}$	Input LOW Current				$\pm 100$	$\mu\text{A}$
$I_{BBH}$ $I_{BBL}$	Bus Hold Sustain Current on Bus Hold Input <sup>[9]</sup>	$V_{CC}=\text{Min.}$ $V_I=2.0V$ $V_I=0.8V$	-50 +50			$\mu\text{A}$ $\mu\text{A}$
$I_{BHHO}$ $I_{BHLO}$	Bus Hold Overdrive Current on Bus Hold Input <sup>[9]</sup>	$V_{CC}=\text{Max.}, V_I=1.5V$			$\pm 500$	$\mu\text{A}$
$I_{OZH}$	High Impedance Output Current (Three-State Output pins)	$V_{CC}=\text{Max.}, V_{OUT}=V_{CC}$			$\pm 1$	$\mu\text{A}$
$I_{OZL}$	High Impedance Output Current (Three-State Output pins)	$V_{CC}=\text{Max.}, V_{OUT}=\text{GND}$			$\pm 1$	$\mu\text{A}$
$I_{OS}$	Short Circuit Current <sup>[7]</sup>	$V_{CC}=\text{Max.}, V_{OUT}=\text{GND}$	-60	-135	-240	mA
$I_{OFF}$	Power-Off Disable	$V_{CC}=0V, V_{OUT}\leq 4.5V$			$\pm 100$	$\mu\text{A}$
$I_{CC}$	Quiescent Power Supply Current	$V_{IN}\leq 0.2V,$ $V_{IN}\geq V_{CC}-0.2V$ $V_{CC}=\text{Max.}$			+40	$\mu\text{A}$
$\Delta I_{CC}$	Quiescent Power supply Current (TTL inputs HIGH)	$V_{IN}=V_{CC}-0.6V$ <sup>[8]</sup> $V_{CC}=\text{Max.}$			+350	$\mu\text{A}$

**Electrical Characteristics For Balanced Drive Devices** Over the Operating Range  $V_{CC}=2.7V$  to  $3.6V$ 

Parameter	Description	Test Conditions	Min.	Typ. <sup>[5]</sup>	Max.	Unit
$I_{ODL}$	Output LOW Dynamic Current <sup>[7]</sup>	$V_{CC}=3.3V, V_{IN}=V_{IH}$ or $V_{IL}, V_{OUT}=1.5V$	45		180	mA
$I_{ODH}$	Output HIGH Dynamic Current <sup>[7]</sup>	$V_{CC}=3.3V, V_{IN}=V_{IH}$ or $V_{IL}, V_{OUT}=1.5V$	-45		-180	mA
$V_{OH}$	Output HIGH Voltage	$V_{CC}=\text{Min.}, I_{OH}=-0.1\text{ mA}$ $V_{CC}=\text{Min.}, I_{OH}=-8\text{ mA}$ $V_{CC}=3.0V, I_{OH}=-24\text{ mA}$	$V_{CC}-0.2$ 2.4 <sup>[10]</sup> 2.0			V V V
$V_{OL}$	Output LOW Voltage	$V_{CC}=\text{Min.}, I_{OL}=0.1\text{ mA}$ $V_{CC}=\text{Min.}, I_{OL}=24\text{ mA}$		0.3	0.55	V

**Notes:**

9. Pins with bus hold are described in Pin Description.  
10.  $V_{OH}=V_{CC}-0.6V$  at rated current.

**Capacitance<sup>[6]</sup>** ( $T_A = +25^\circ\text{C}, f = 1.0\text{ MHz}$ )

Parameter	Description	Test Conditions	Typ. <sup>[5]</sup>	Max.	Unit
$C_{IN}$	Input Capacitance	$V_{IN} = 0V$	4.5	6.0	pF
$C_{OUT}$	Output Capacitance	$V_{OUT} = 0V$	5.5	8.0	pF

**Power Supply Characteristics**

Parameter	Description	Test Conditions	Typ. <sup>[5]</sup>	Max.	Unit	
$I_{CCD}$	Dynamic Power Supply Current <sup>[11]</sup>	$V_{CC}=\text{Max.}$ , One Input Toggling, 50% Duty Cycle, Outputs Open, $\overline{OE}=\text{GND}$	$V_{IN}=V_{CC}$ or $V_{IN}=\text{GND}$	50	75	$\mu\text{A}/\text{MHz}$
$I_C$	Total Power Supply Current <sup>[12]</sup>	$V_{CC}=\text{Max.}$ , $f_1=10\text{ MHz}$ , 50% Duty Cycle, Outputs Open, One Bit Toggling, $\overline{OE}=\text{GND}$	$V_{IN}=V_{CC}$ or $V_{IN}=\text{GND}$	0.5	0.8	mA
			$V_{IN}=V_{CC}-0.6\text{V}$ or $V_{IN}=\text{GND}$	0.5	0.8	mA
		$V_{CC}=\text{Max.}$ , $f_1=2.5\text{ MHz}$ , 50% Duty Cycle, Outputs Open, Sixteen Bits Toggling, $\overline{OE}=\text{GND}$	$V_{IN}=V_{CC}$ or $V_{IN}=\text{GND}$	2.0	3.0 <sup>[13]</sup>	mA
			$V_{IN}=V_{CC}-0.6\text{V}$ or $V_{IN}=\text{GND}$	2.0	3.3 <sup>[13]</sup>	mA

**Switching Characteristics Over the Operating Range  $V_{CC}=3.0\text{V}$  to  $3.6\text{V}$ <sup>[14,15]</sup>**

Parameter	Description	CY74FCT163245A CY74FCT163H245A		CY74FCT163245C CY74FCT163H245C		Unit	Fig. No. <sup>[16]</sup>
		Min.	Max.	Min.	Max.		
$t_{PLH}$ $t_{PHL}$	Propagation Delay Data to Output	1.5	4.8	1.5	4.1	ns	1, 3
$t_{PZH}$ $t_{PZL}$	Output Enable Time	1.5	6.2	1.5	5.8	ns	1, 7, 8
$t_{PHZ}$ $t_{PLZ}$	Output Disable Time	1.5	5.6	1.5	5.2	ns	1, 7, 8
$t_{SK(O)}$	Output Skew <sup>[17]</sup>		0.5		0.5	ns	—

**Notes:**

- This parameter is not directly testable, but is derived for use in Total Power Supply calculations.
- $I_C = I_{\text{QUIESCENT}} + I_{\text{INPUTS}} + I_{\text{DYNAMIC}}$   
 $I_C = I_{CC} + \Delta I_{CC} D_H N_T + I_{CCD} (f_0/2 + f_1 N_1)$   
 $I_{CC}$  = Quiescent Current with CMOS input levels  
 $\Delta I_{CC}$  = Power Supply Current for a TTL HIGH input ( $V_{IN}=3.4\text{V}$ )  
 $D_H$  = Duty Cycle for TTL inputs HIGH  
 $N_T$  = Number of TTL inputs at  $D_H$   
 $I_{CCD}$  = Dynamic Current caused by an input transition pair (HLH or LHL)  
 $f_0$  = Clock frequency for registered devices, otherwise zero  
 $f_1$  = Input signal frequency  
 $N_1$  = Number of inputs changing at  $f_1$   
 All currents are in milliamps and all frequencies are in megahertz.
- Values for these conditions are examples of the  $I_{CC}$  formula. These limits are specified but not tested.
- Minimum limits are specified but not tested on Propagation Delays.
- For  $V_{CC}=2.7$ , propagation delay, output enable and output disable times should be degraded by 20%.
- See "Parameter Measurement Information" in the General Information section.
- Skew between any two outputs of the same package switching in the same direction. This parameter is ensured by design.

**Ordering Information CY74FCT163245**

Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
4.1	CY74FCT163245CPACT	Z48	48-Lead (240-Mil) TSSOP	Industrial
	CY74FCT163245CPVC/PVCT	O48	48-Lead (300-Mil) SSOP	
4.8	CY74FCT163245APACT	Z48	48-Lead (240-Mil) TSSOP	Industrial
	CY74FCT163245APVC/PVCT	O48	48-Lead (300-Mil) SSOP	

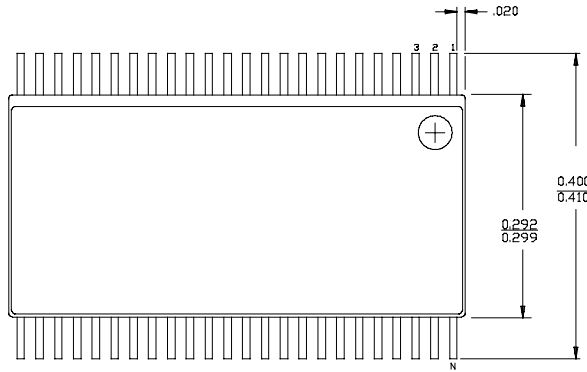
**Ordering Information CY74FCT163H245**

Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
4.1	74FCT163H245CPACT	Z48	48-Lead (240-Mil) TSSOP	Industrial
	CY74FCT163H245CPVC	O48	48-Lead (300-Mil) SSOP	
	74FCT163H245CPVCT	O48	48-Lead (300-Mil) SSOP	
4.8	CY74FCT163H245APVC	O48	48-Lead (300-Mil) SSOP	Industrial
	74FCT163H245APVCT	O48	48-Lead (300-Mil) SSOP	

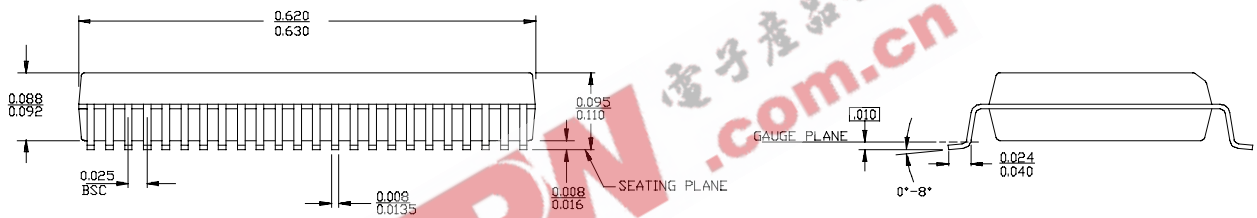
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**Package Diagrams**

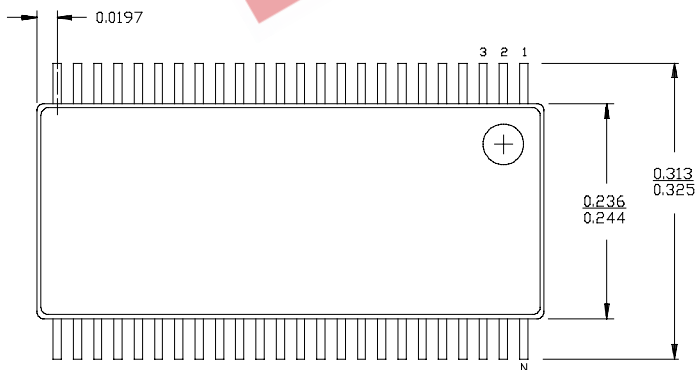
**48-Lead Shrunken Small Outline Package O48**



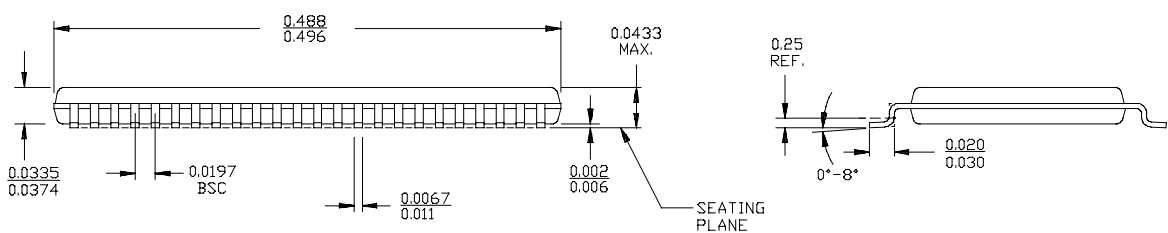
DIMENSIONS IN INCHES MIN.  
MAX.



**48-Lead Thin Shrunken Small Outline Package Z48**



DIMENSIONS IN INCHES MIN.  
MAX.



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